

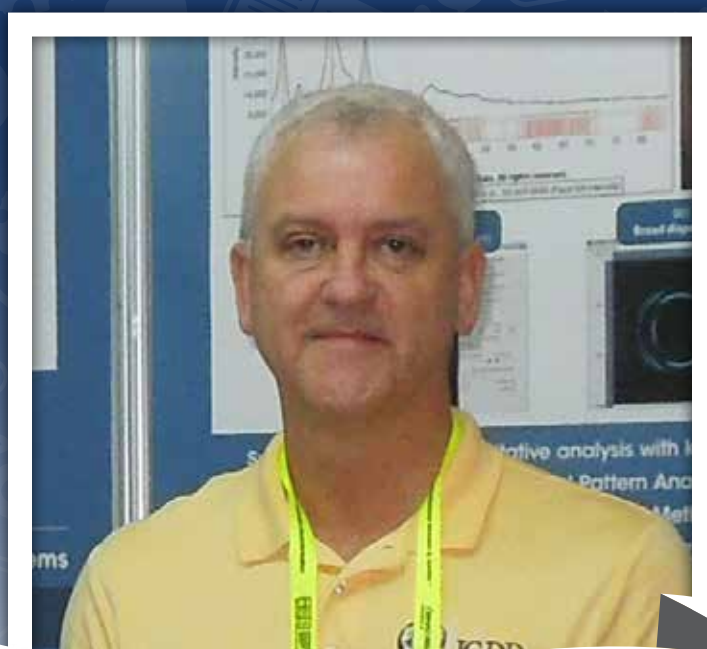
ICDD PRESS RELEASE



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ICDD Announces the Appointment of our *New Executive Director*



Tom Blanton

The International Centre for Diffraction Data (ICDD®) is pleased to announce that Tom Blanton has been named as ICDD's new Executive Director.

Tom is a long-time ICDD member, an ICDD Distinguished Fellow, and past Director and Chairman of the Board of Directors. He joined the ICDD staff in 2013 as Publication Manager, and was later promoted to Principal Scientist and Database Manager. Prior to joining the ICDD staff, Tom graduated from Emory University in Atlanta, Georgia and was a member of the research staff at Eastman Kodak Company in Rochester, New York. While at Kodak, he served a dual role as an Analytical Scientist and Materials Characterization Scientist, reaching the position of Senior Principal Scientist. During his tenure at Eastman Kodak, Tom assumed a leadership role where he supervised an X-ray Spectroscopy laboratory and invented, developed, and commercialized materials. He is the co-inventor for 46 U.S. and 60 international patents, author or co-author of 180+ external publications including four book chapters; and author or co-author on over 275 external presentations.

Tom's extensive background in X-ray diffraction, his broad and varied knowledge of ICDD, its products and services, along with his experience in management and R&D for product development, will facilitate his successful transition to his new role as ICDD's Executive Director.



Have you connected with ICDD yet?

Stay informed with information about upcoming exhibits, meetings, workshops, product tutorials, and pictures from events we've attended around the world!



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